

**4D-S Ltd**

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# Abstract

- **4DS has developed a robust ReRAM material system, MOHJO™:**
  - High cycle life
  - Low power dissipation
  - Good data retention
  - Reduced manufacturing time and cost
- **MOHJO™ is implemented as a back end process atop standard CMOS flow**
- **MOHJO™ has a low current reset state that enables large blocks of memory to be erased enabling a number of interesting applications**
- **MOHJO™ can be particularly useful in SSD where it can result in a 100x reduction of energy consumption.**

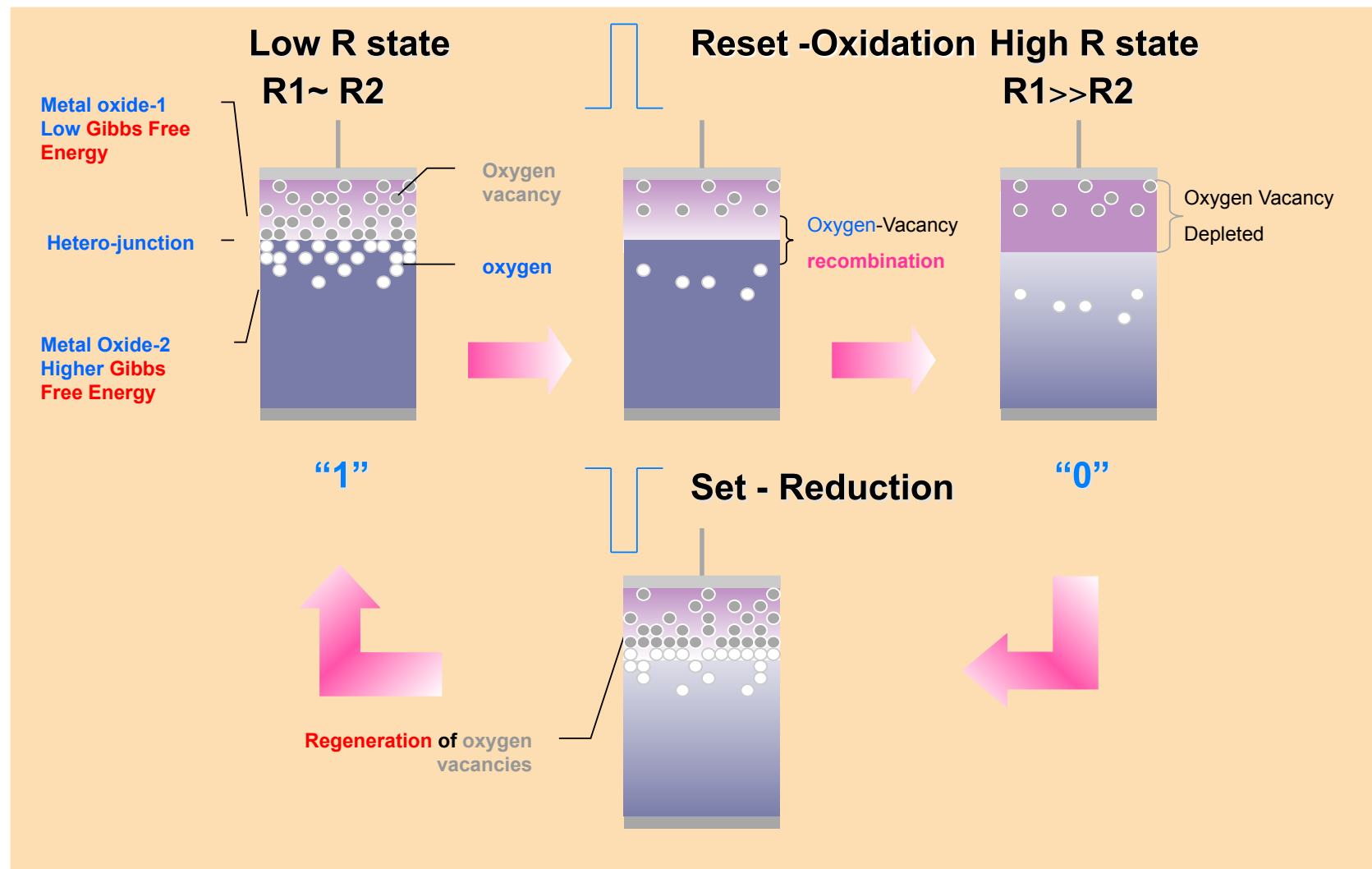


# Technology – Key Attributes

**4DS' MOHJO™ memory is high speed, non-volatile, low power, low cost and is able to be produced using existing semiconductor manufacturing equipment**

|                        |  |   |  |
|------------------------|--|---|--|
| <b>LOW COST</b>        | <ul style="list-style-type: none"><li>• Produced using +1 to 4 mask steps when combined with standard CMOS process (as compared to +16 to 20 mask steps for FLASH) for the memory core.</li><li>• Scalable and repeatable proprietary wafer process for mass production.</li></ul> | <b>EXISTING FAB EQUIPMENT / PROCESSES</b> | <ul style="list-style-type: none"><li>• Simple integration into fabs, process steps utilizes established fabrication equipment and processes.</li><li>• Proprietary process is implementable as customized module on existing fabrication tools.</li></ul> |
| <b>LOW POWER</b>       | <ul style="list-style-type: none"><li>• Low voltage operation and low current, making it attractive for a variety of applications</li></ul>  | <b>DENSITY</b>                            | <ul style="list-style-type: none"><li>• High density 4F<sup>2</sup> with diode/6F<sup>2</sup> with transistor</li></ul>  |
| <b>LOW TEMPERATURE</b> | <ul style="list-style-type: none"><li>• Memory is formed with a proprietary low temperature process similar to CMOS back end of line (BEOL) temperatures.</li></ul>  | <b>LONG CYCLE LIFE</b>                    | <ul style="list-style-type: none"><li>• 10<sup>9</sup></li></ul>   |
| <b>HIGH SPEED</b>      | <ul style="list-style-type: none"><li>• Fast Read/Write</li></ul>  | <b>RELIABILITY</b>                        | <ul style="list-style-type: none"><li>• 10 year data retention</li></ul>   |
| <b>SCALABILITY</b>     | <ul style="list-style-type: none"><li>• Tested at 30nm, project down to 10nm and below.</li></ul>  | <b>CMOS COMPATIBLE</b>                    | <ul style="list-style-type: none"><li>• Process is CMOS compatible.</li></ul>  |

# Metal Oxide Hetero-Junction Operation (MOHJO™)



# Technology – Relative Comparison



**4DS' MOHJO™ memory compares very favourably to the best characteristics of competing solutions**

|                           | Flash           | STT              | PCM             | MOJHO           |
|---------------------------|-----------------|------------------|-----------------|-----------------|
| Density (F <sup>2</sup> ) | 1-4             | 20-60            | 4-16            | 4/(# layers)    |
| Energy per bit (pJ)       | 100             | 0.1-2.5          | 2-2.5           | 0.2-3           |
| Read Time (ns)            | 100000          | 10-35            | 10-50           | 10-50           |
| Write Time (ns)           | 100000          | 10-90            | 50-500          | 10-50           |
| Endurance                 | 10 <sup>4</sup> | 10 <sup>15</sup> | 10 <sup>9</sup> | 10 <sup>9</sup> |
| Retention                 | Years           | Years            | Years           | Years           |

# Technology – Relative Positioning

Table ERD9 Target Device and System Specifications for SCM

| Parameter          | Benchmark [A]                          |  |                                       | Target                                 |  | MOHJO™                                 |
|--------------------|--|--|---------------------------------------|--|--|--|
|                    | HDD [B]                                | NAND flash [C]                         | DRAM                                  | Memory-type SCM                        | Storage-type SCM                       |  |
| Read/Write latency | 3-5 ms                                 | ~100µs<br>(block erase ~1 ms)          | <100 ns                               | <100 ns                                | 1-10µs                                 | 10ns to 50ns                           |
| Endurance (cycles) | unlimited                              | 10 <sup>4</sup> -10 <sup>5</sup>       | unlimited                             | >10 <sup>9</sup>                       | >10 <sup>6</sup>                       | >10 <sup>9</sup>                       |
| Retention          | >10 years                              | ~10 years                              | 64 ms                                 | >5 days                                | ~10 years                              | ~10 years                              |
| ON power (W/GB)    | ~0.04                                  | ~0.01-0.04                             | 0.4                                   | <0.4                                   | <0.04                                  | <0.04                                  |
| Areal density      | ~ 10 <sup>11</sup> bit/cm <sup>2</sup> | ~ 10 <sup>10</sup> bit/cm <sup>2</sup> | ~ 10 <sup>9</sup> bit/cm <sup>2</sup> | ~ 10 <sup>10</sup> bit/cm <sup>2</sup> | ~ 10 <sup>10</sup> bit/cm <sup>2</sup> | ~ 10 <sup>10</sup> bit/cm <sup>2</sup> |
| Cost (\$/GB)       | 0.1                                    | 2                                      | 10                                    | <10                                    | <3-4                                   | <1                                     |

Notes for Table ERD9:

[A] The benchmark numbers are representative values, which may have significant variations in specific products

[B] Enterprise class

[C] Single-level cell (SLC)

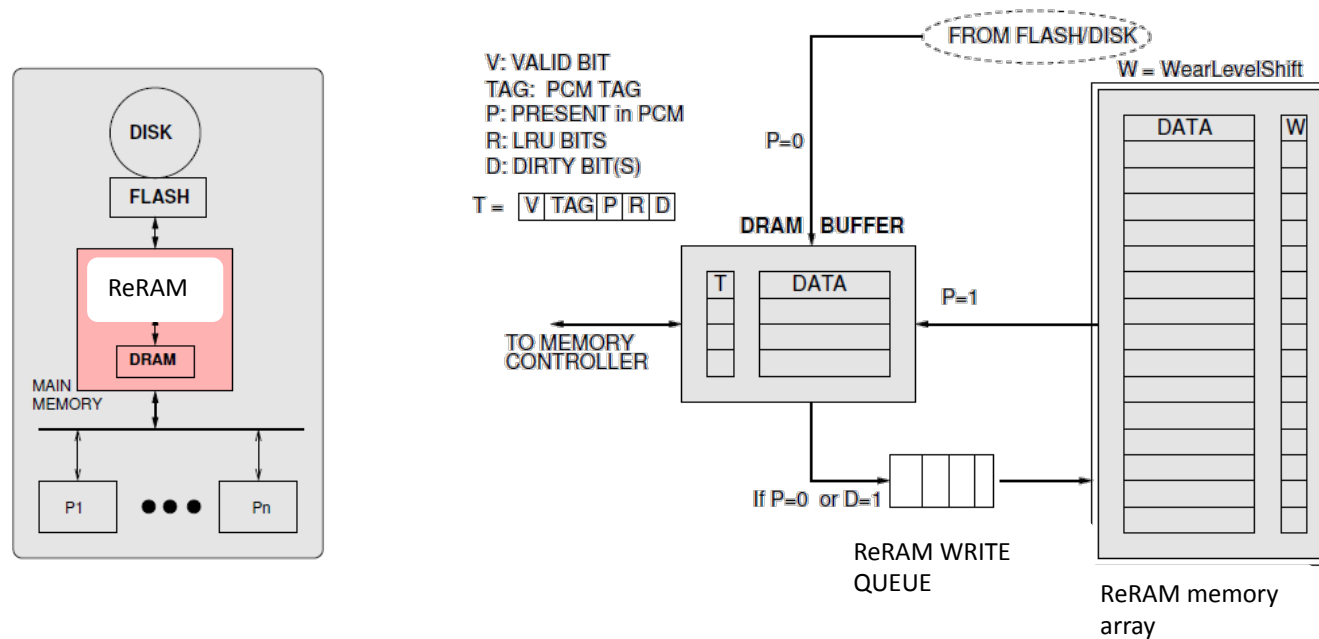
The International Technology Roadmap for Semiconductors, 2011 Edition (latest)

# Advantages of Asymmetrical Hysteresis

- **Extremely low power operation on the reset side**
- **Low power operation enables a bulk or block erase feature; which in Flash memory type applications would provide a drop in, higher performance replacement using current flash controllers.**
- **Low power bulk erase is also highly desirable feature in security applications where the data may need to be wiped out quickly.**
- **Of note the bulk erase is a feature not a requirement as in many current nonvolatile memories. Both the Set and Reset operations can be performed on a byte by byte basis.**

# Implementation 1: Cache/Working memory

## DRAM/ReRAM Hybrid Cache



Graphics borrowed from Qureshi HPAC 2009



## Implementation 2: SSD File Storage

- Utilizing ReRAM to replace FLASH in SSD file storage
- 4DS ReRAM performance exceeds high end flash

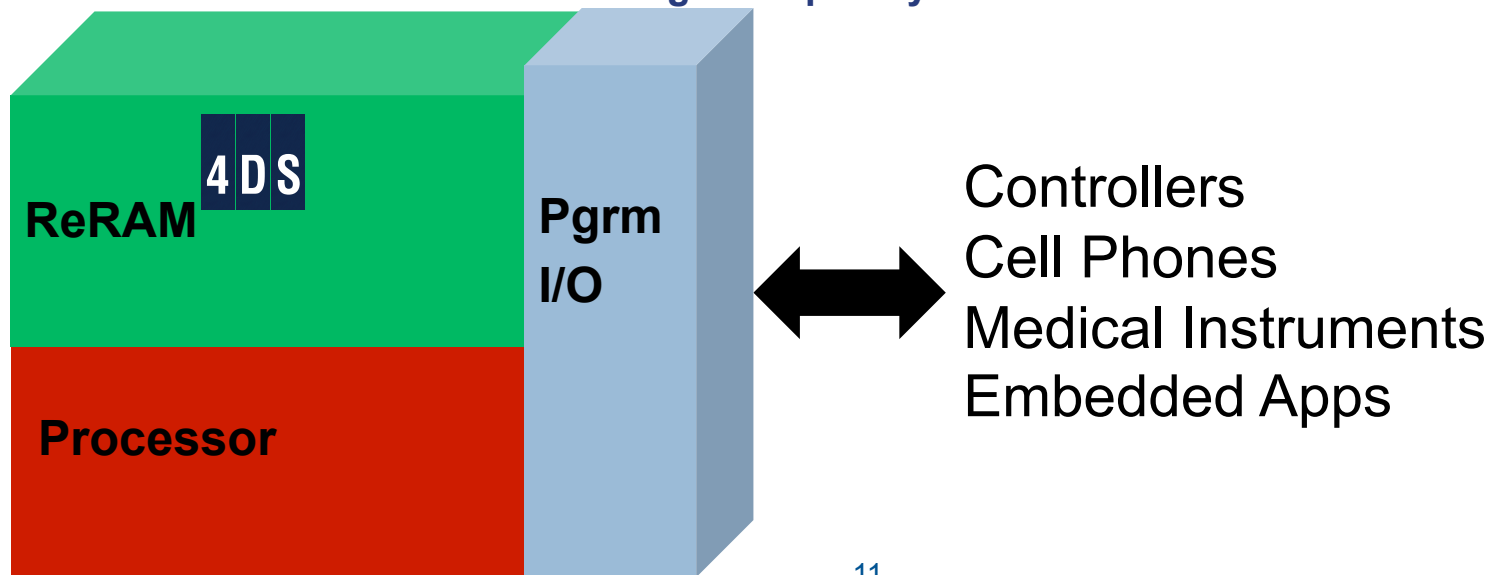
|                | Flash                        | MOJHO™     |
|----------------|------------------------------|------------|
| 1.Voltage:     | < 15V                        | Better     |
| 2.Endurance:   | > 10 <sup>4</sup> W/E cycles | Better     |
| 3.Scalability: | < ~18 nm, 3D stackable       | Comparable |
| 4.W/E time:    | < 100 μs                     | Better     |
| 5.Retention:   | > 10 years                   | Comparable |

- In spite of the excellent potential this transistion will take a while due to the billons invested in Flash infrastructure



# 4DS MOHJO™ Embedded Memory

- Lower cost and higher performance than embedded flash with the updating capability that OTP memories lack
- Optimizes processor speed and reduces power consumption of electronic devices.
- High Security applications
- The memory would be implemented in a 1T/1R configuration for embedded applications instead of 1D/1R to reduce the design complexity on the smaller embedded memories.



# High Security in Embedded Configuration

- One of the major advantages of embedding memory is improved security due to the elimination of external and easily accessible bus lines.
- Once the memory is embedded the next level of security is determined by how easily a hacker can determine what is inside the memory.
- The 4DS MOHJO™ memory is very secure.
  - Extremely low power and high speed makes thermal detection extremely difficult.
  - No visible difference between 1's and 0's in de-processing
    - No physical links or other features.
  - Extremely low voltage contrast in the array.